

GN-MEBA Jussieu Paris, 2-3 Novembre, 2004

3. LES CATHODES FROIDES SSE :

Une nouvelle approche avec des couches ultra-minces

Motivation: cathodes froides pour des applications industrielles

Objectif: une miniaturisation poussée de systèmes basés sur des faisceaux d'électrons

Développements:

- * écrans plats à émission de champ
- * générateurs de rayons X miniaturisés
- * microcanon pour lithographie électronique
- * réfrigérateur local par effet Nottingham
- * spectromètres miniatures,

Conditions requises pour un développement industriel

Trois principales:

- ✓ (1) source : froide / émission électronique à température ambiante
- ✓ (2) fabrication : faible coût et compatible avec une grande série
- ✓ (3) qualité requise: émission stable dans un vide médiocre
(100A/cm² - 10⁻⁷ Torr)

Deux nouvelles approches

Première approche avec de
**nouvelles techniques de
fabrication :**

- * les nanotubes de C
 - * les nanoperoles de C
- (travail de sortie ~4 eV)

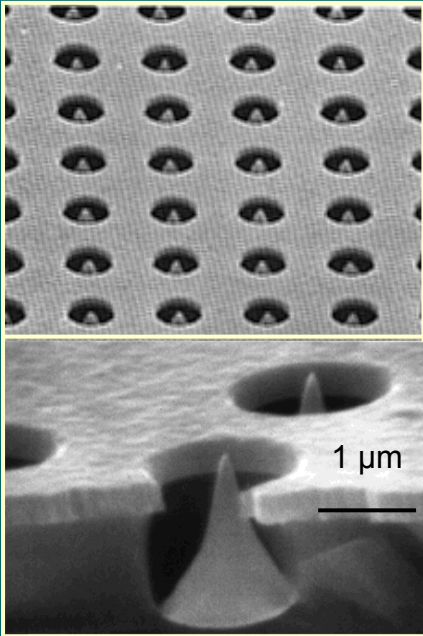
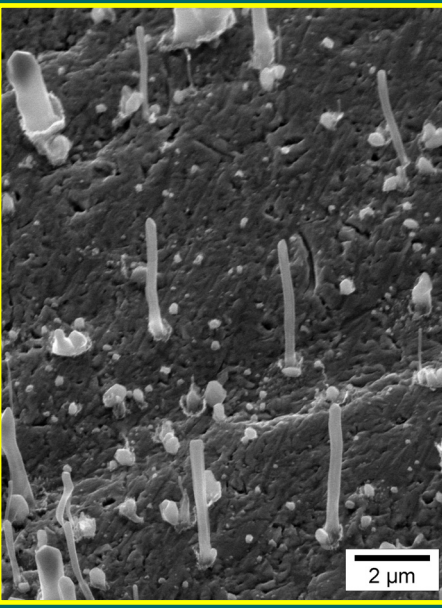
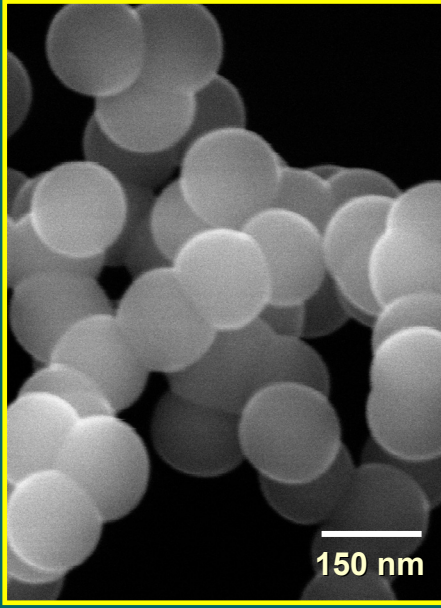
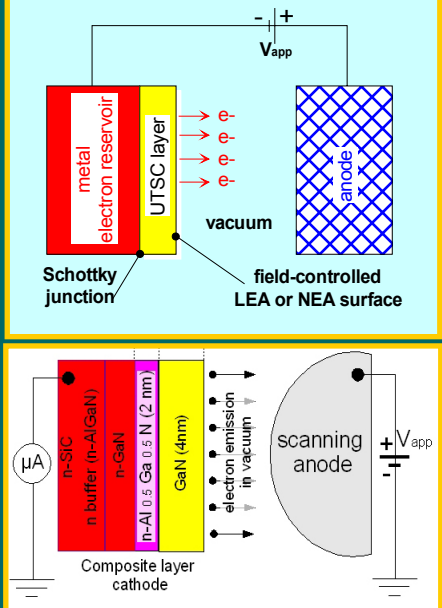
Seconde approche
**avec de nouvelles structures
de surface:**

Les cathodes SSE à couches
ultra-minces
(travail de sortie ~0.3 eV)

Conditions requises pour un développement industriel

Trois principales:

- ✓ (1) source : froide / émission électronique à température ambiante
- ✓ (2) fabrication : faible coût et compatible avec une grande série
- ✓ (3) qualité requise: émission stable dans un vide médiocre
($100\text{A}/\text{cm}^2 - 10^{-7}$ Torr)

Pointes de Spindt (1968, 1980)	Nanotubes de C (1991, Lyon 1999)	Nanoperles de C (Lyon 2003)	Cathodes SSE (Lyon 1999, 2003)
			

Conditions requises pour un développement industriel

Trois principales:

- ✓ (1) source : froide / émission électronique à température ambiante
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(100A/cm² - 10⁻⁷ Torr)

Approach using

the solid-state field controlled emission (SSE) cathodes

(1) * Lowering of the effective work function until 0.1 to 0.5 eV



- * Field emission for electric field ~1/100 of conventional FE field (~50 V/μm)
- * Thermionic emission for temperatures ~ 300 K (RT)

(2)&(3) * Ultra-thin dielectric layers and thin film deposition process

Solid-state field-controlled emission (SSE) cathode

The challenge:

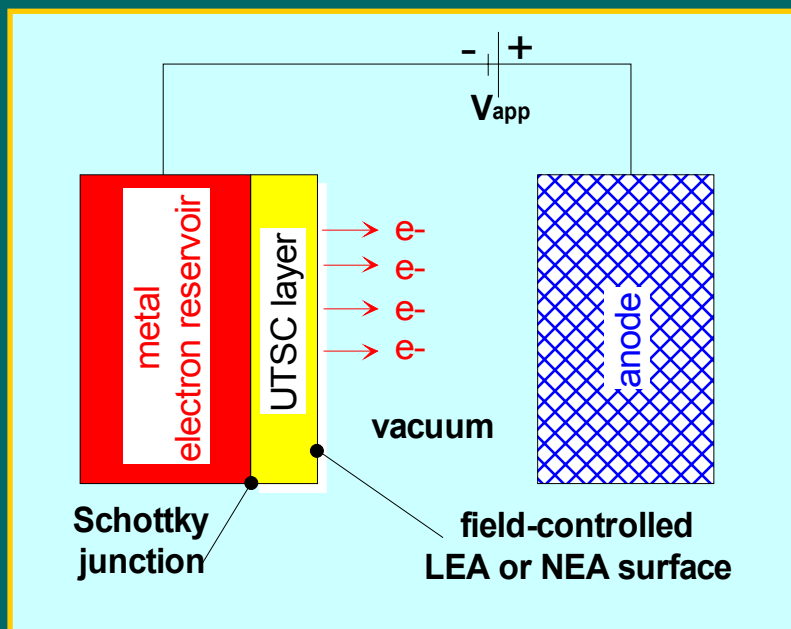
Question: Is there any possibility
to overcome the predominant role of the surface
in the definition of the barrier height ?

Possibilities:

- * low adsorption rate surfaces, i.e. covalent surfaces
- * control of the electron affinity by tuning the solid state electronic structure of the **underneath** layer

Solid-state field-controlled emission (SSE) cathode

Single layer SSE cathode, 1999



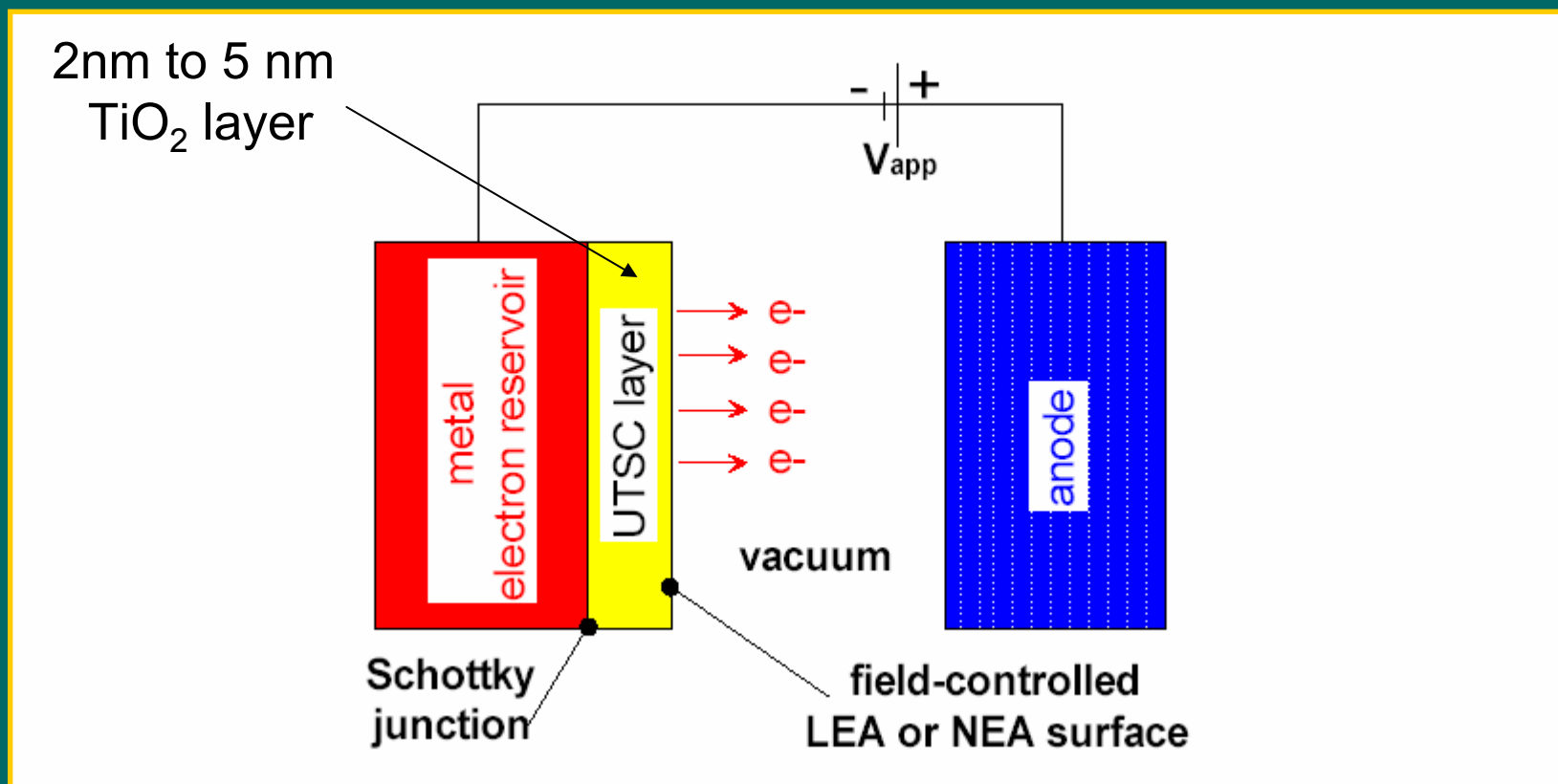
(collaboration: H. Birecki, HP, Palo-Alto)
Phys. Rev. Letters, 85, 864-867 (2000)

Composite layer SSE cathode, 2003



(collaboration: Ray Tsu, UNC Charlotte;
Asif Khan, USC Columbia)
Applied Phys. Letters, 84, 1937-1939 (2004)

Single layer SSE cathode: the structure



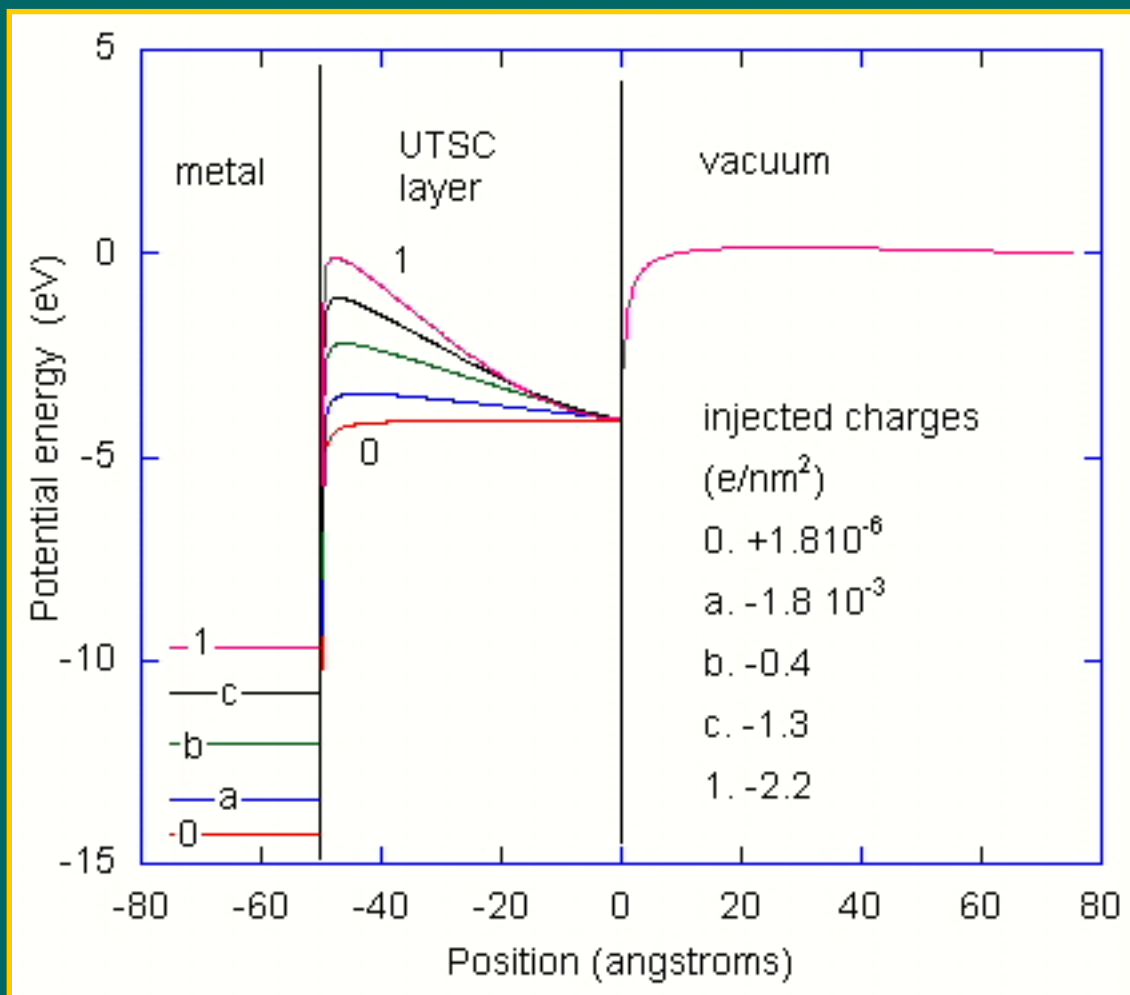
Single layer SSE cathode: the concept

The concept: serial two-step mechanism

- electronic injection from the Schottky junction to create an equilibrium space-charge inside an UTSC (ultra-thin wide band gap semiconductor) which controls the height of the emission barrier $\Delta\Phi_E$
- emission currents from the UTSC surface monitor by an applied field

The fabrication: thin-film deposition techniques

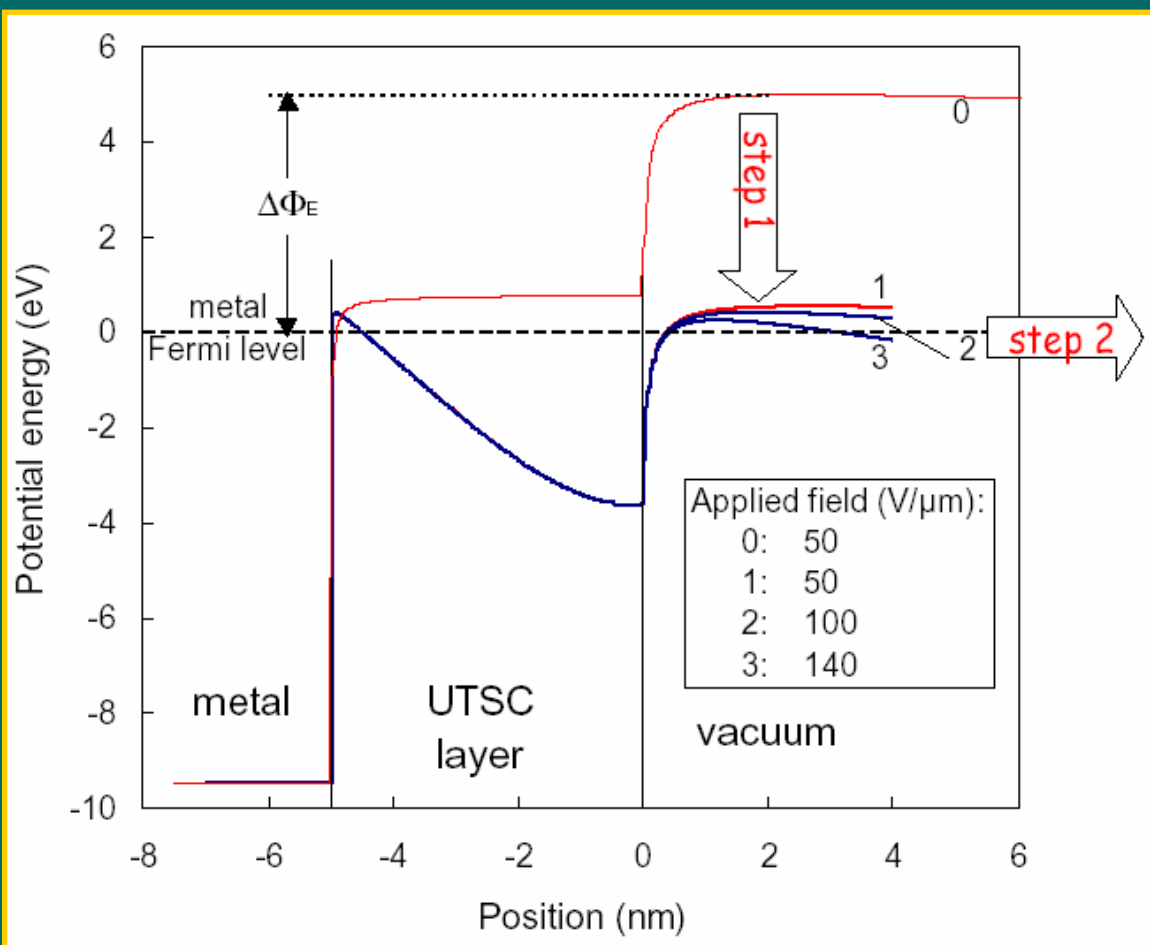
Single layer SSE cathode: the concept



Step 1:

Space charge formation in the UTSC by electron injection through Schottky junction → reduction of the effective emission barrier to a few tenth of eV

Single layer SSE cathode: the concept



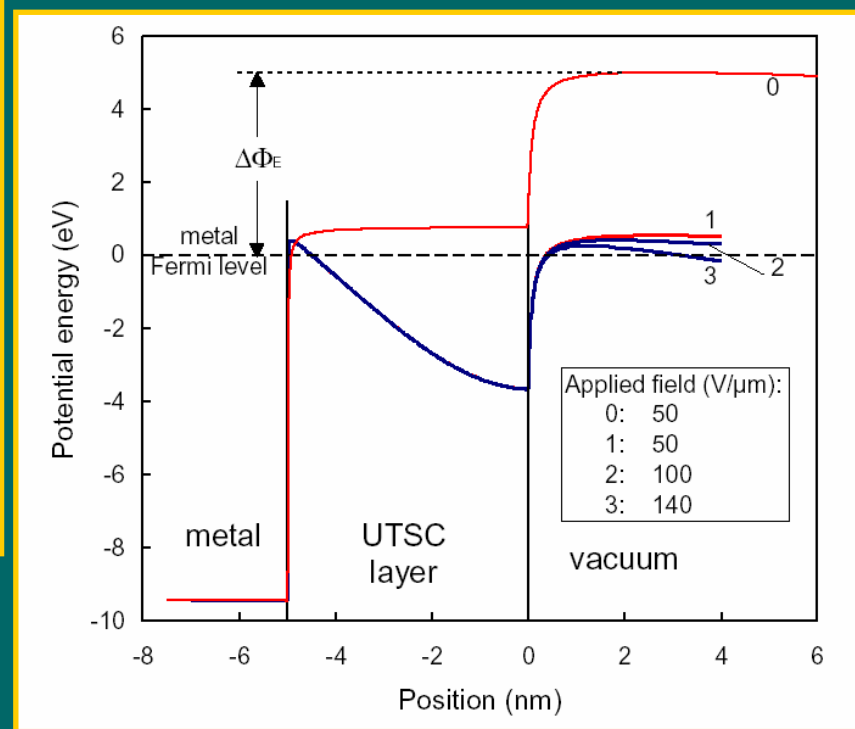
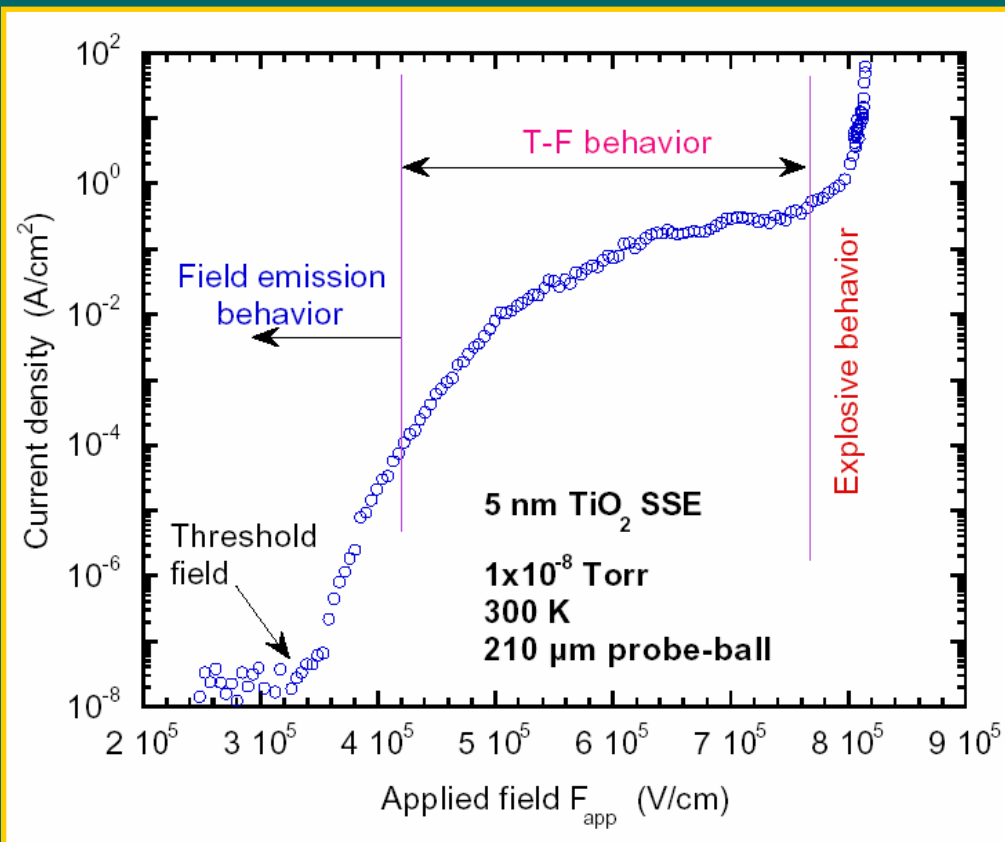
Step 1:

Space charge formation in the UTSC by electron injection through Schottky junction → reduction of the effective emission barrier to a few tenth of eV

Step 2:

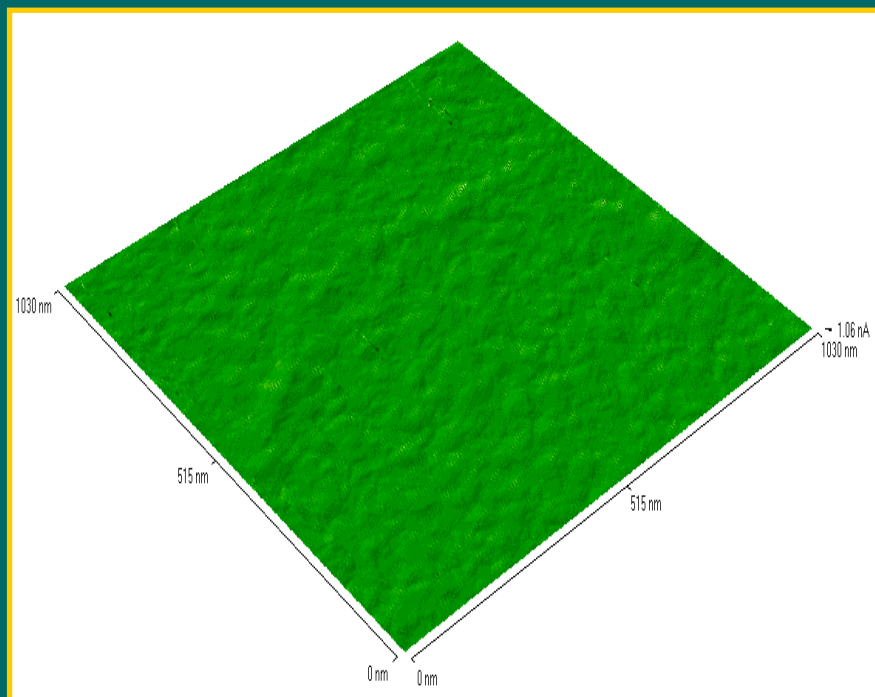
Electron emission through / over the field deformed reduced surface barrier

Single layer SSE cathode: field emission characteristics



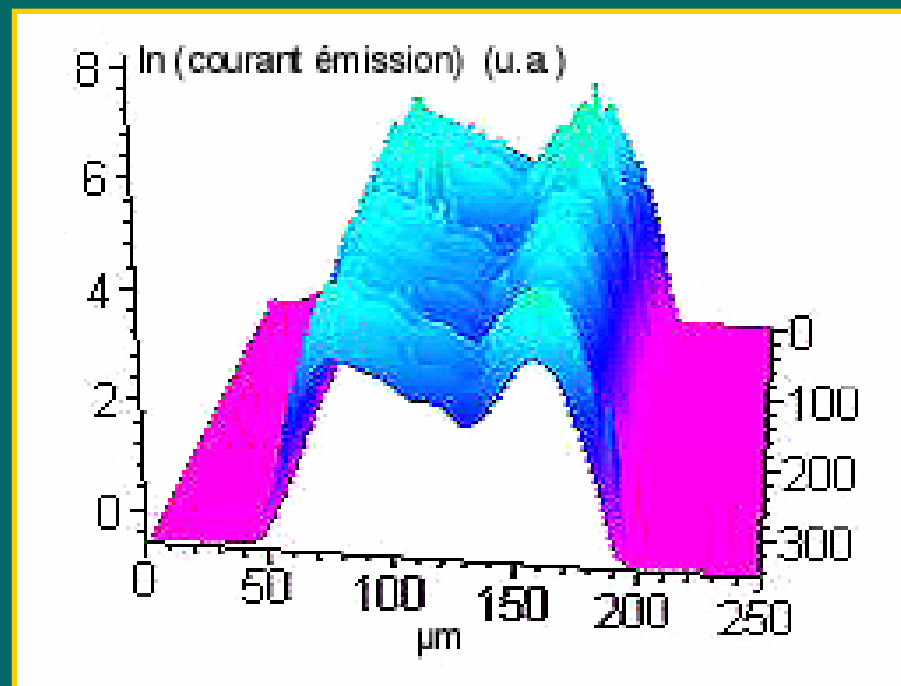
Single layer SSE cathode: field emission characteristics

AFM observation of the TiO_2 surface



$1 \mu\text{m} \times 1 \mu\text{m}$
Mean roughness $\sim 7 \text{ nm}$

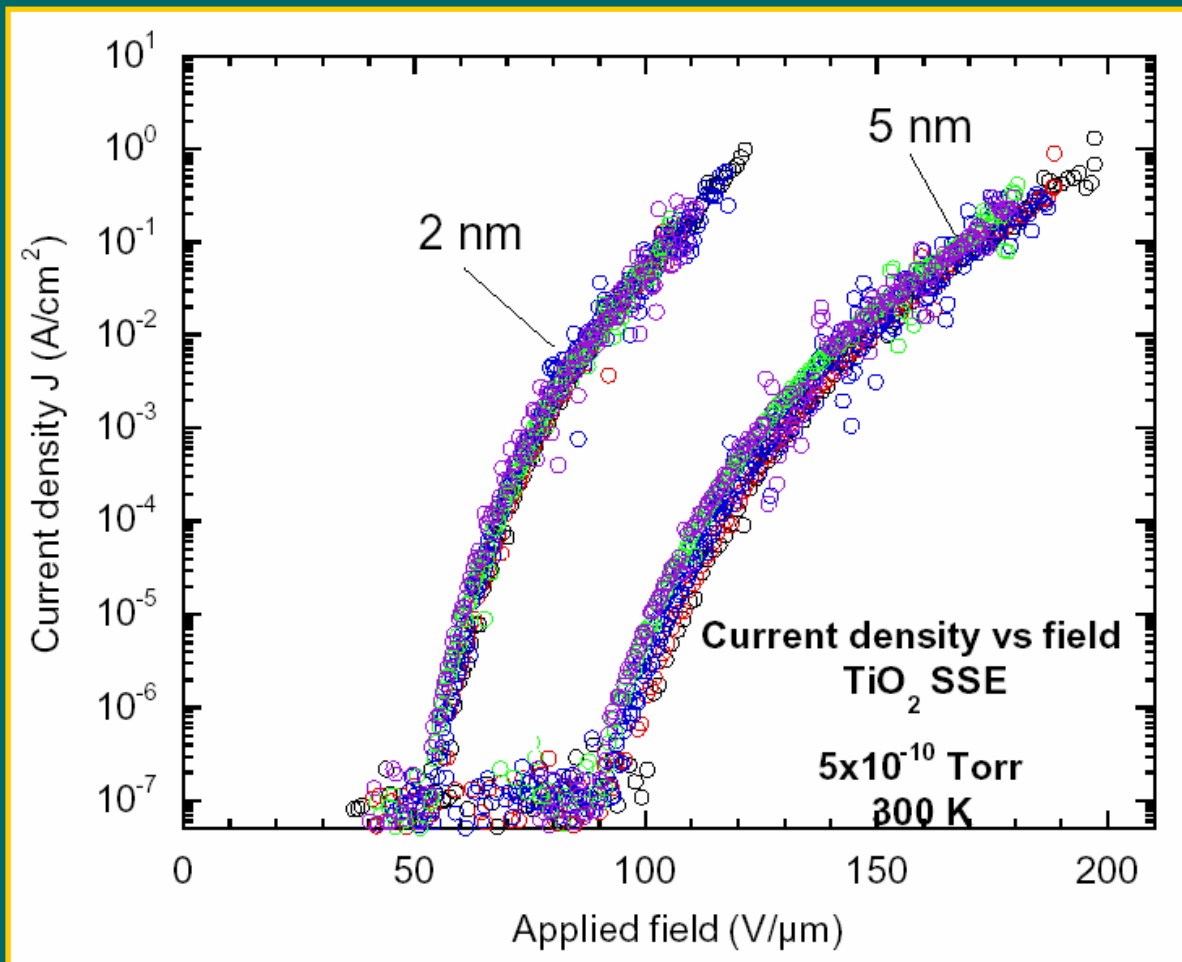
Scanning anode field emission pattern



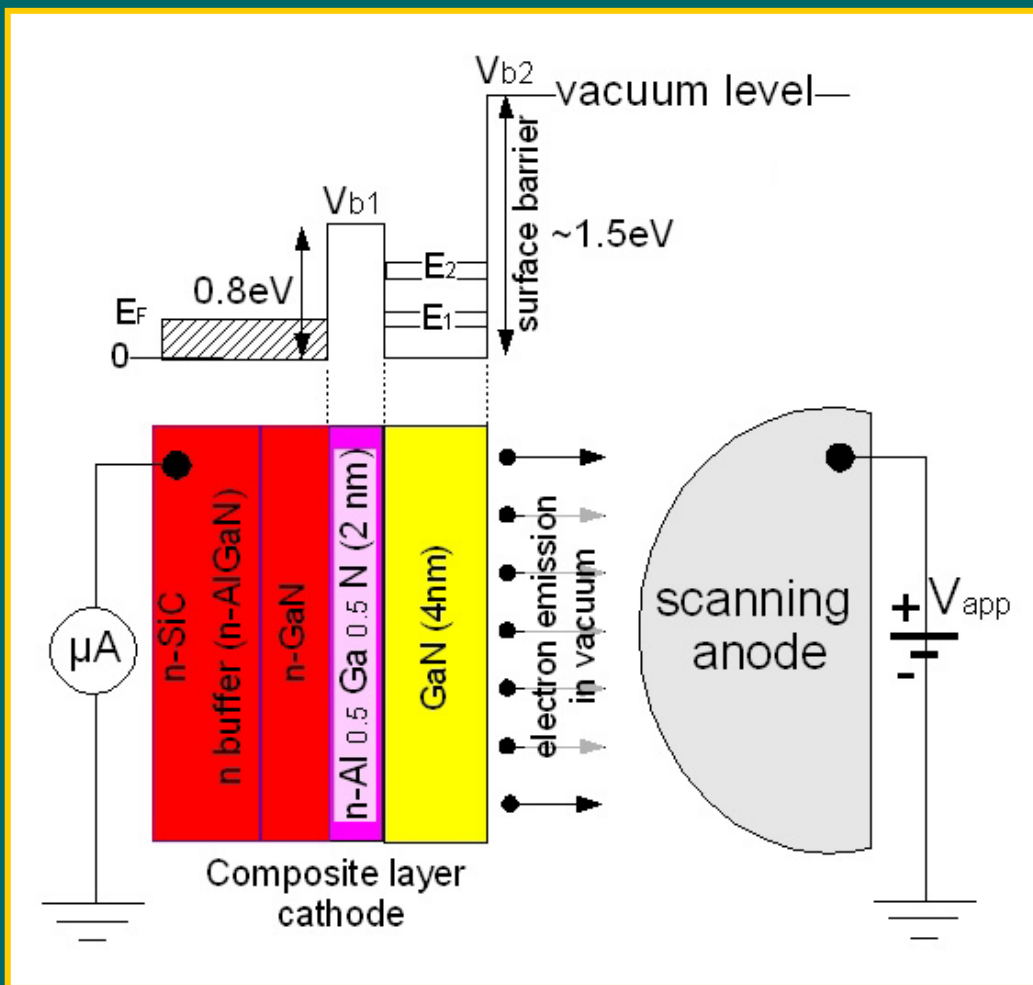
TiO_2 deposited along a $100 \mu\text{m}$ strip
The electron emission is strictly confined over this strip

Single layer SSE cathode: field emission characteristics

UTSC thickness dependence



Nanostructured SSE cathode : the structure



The role of the multilayer :

Presence of a quantum well
at the surface layer



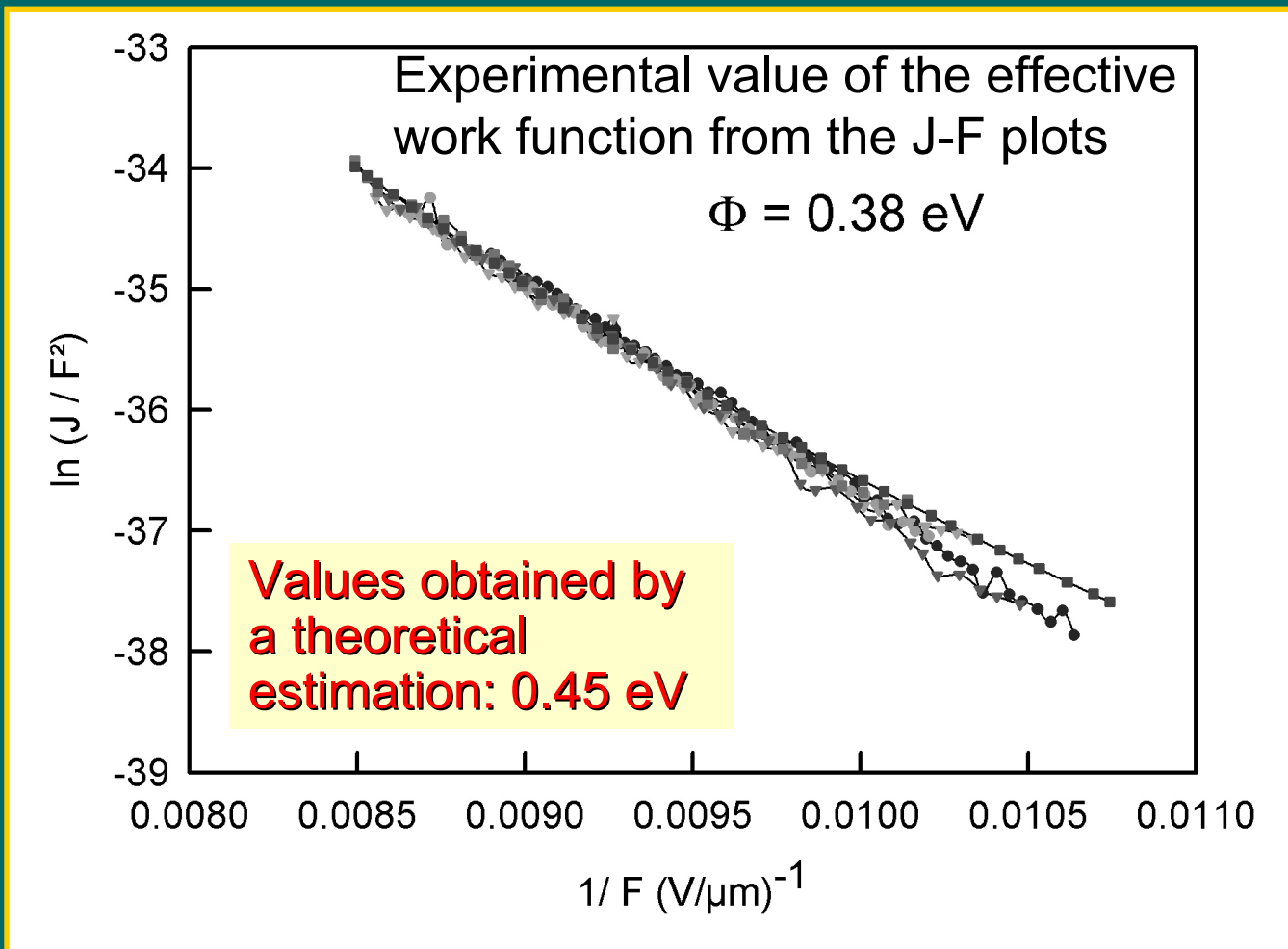
Formation of sub-bands at
discrete energy levels E_1 , E_2



Controlled value for the
space charge at the
surface layer

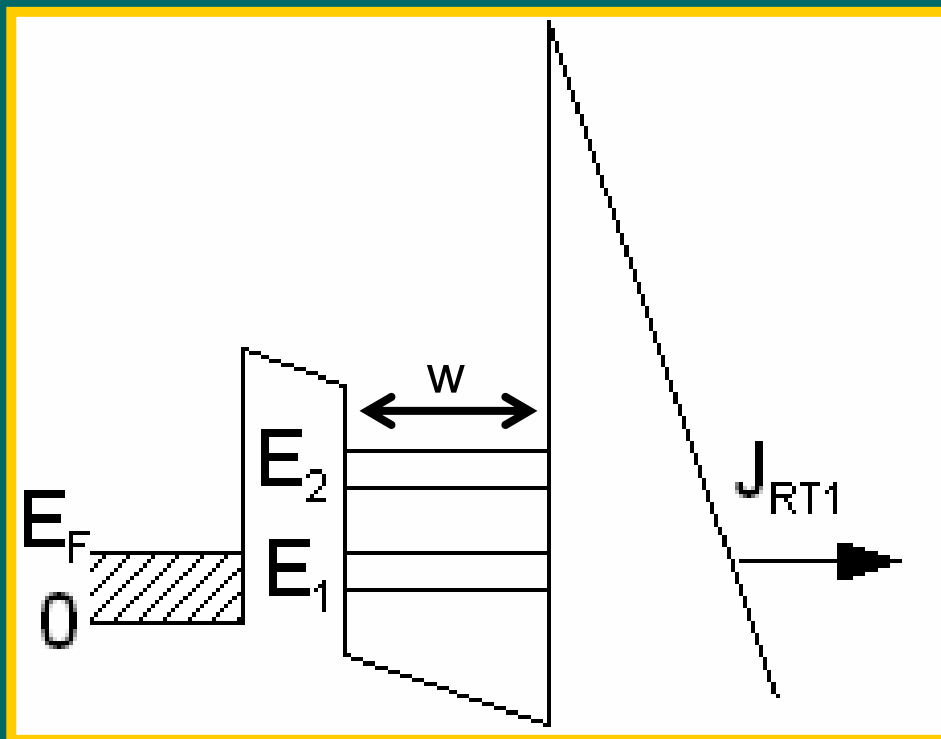
Nanostructured SSE cathode : field emission characteristics

The field emission barrier



Nanostructured SSE cathode : field emission mechanism

Resonant tunneling ?



Tsu, Esaki (APL, 1971)

Lowering of the effective work function only by a few tenths of eV

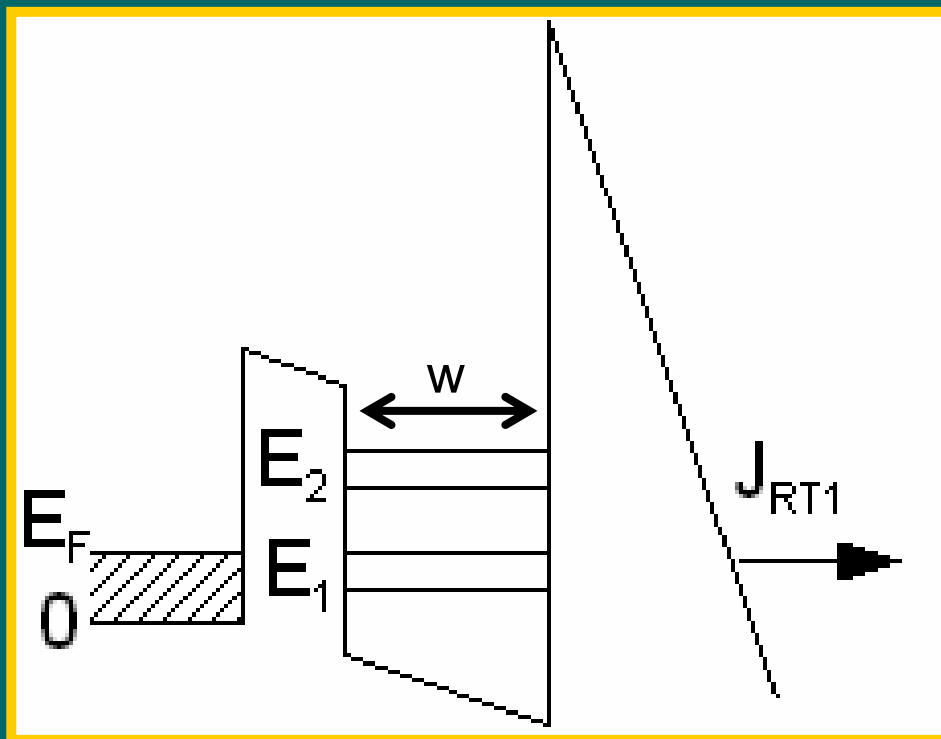
$$\sim (E_1 + [V(w) - V(0)] / 2)$$

with $E_1 = 0.18$ eV

it cannot account for the very low values of * the threshold field for FE
* the surface barrier measured

Nanostructured SSE cathode : field emission mechanism

Lowering of the work function due to space charge in the QW ?



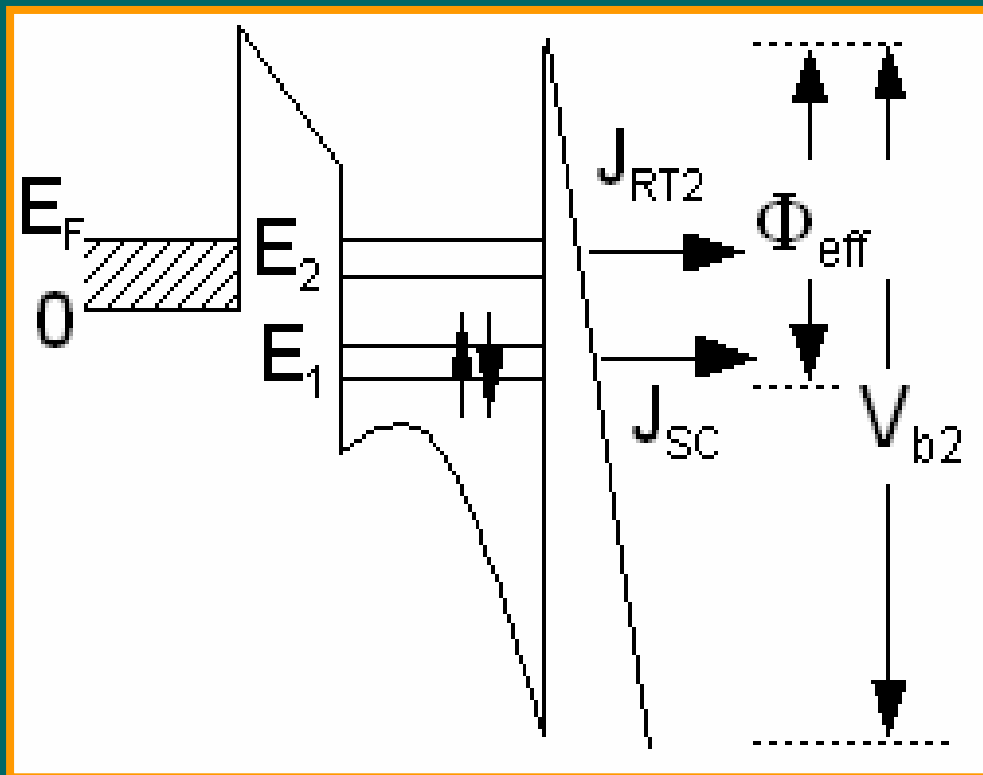
Tsu, Esaki (APL, 1971)

The concept :

* when the 2D-like quantum state is occupied it creates a space charge in the QW

Nanostructured SSE cathode : field emission mechanism

Lowering of the work function due to space charge in the QW ?



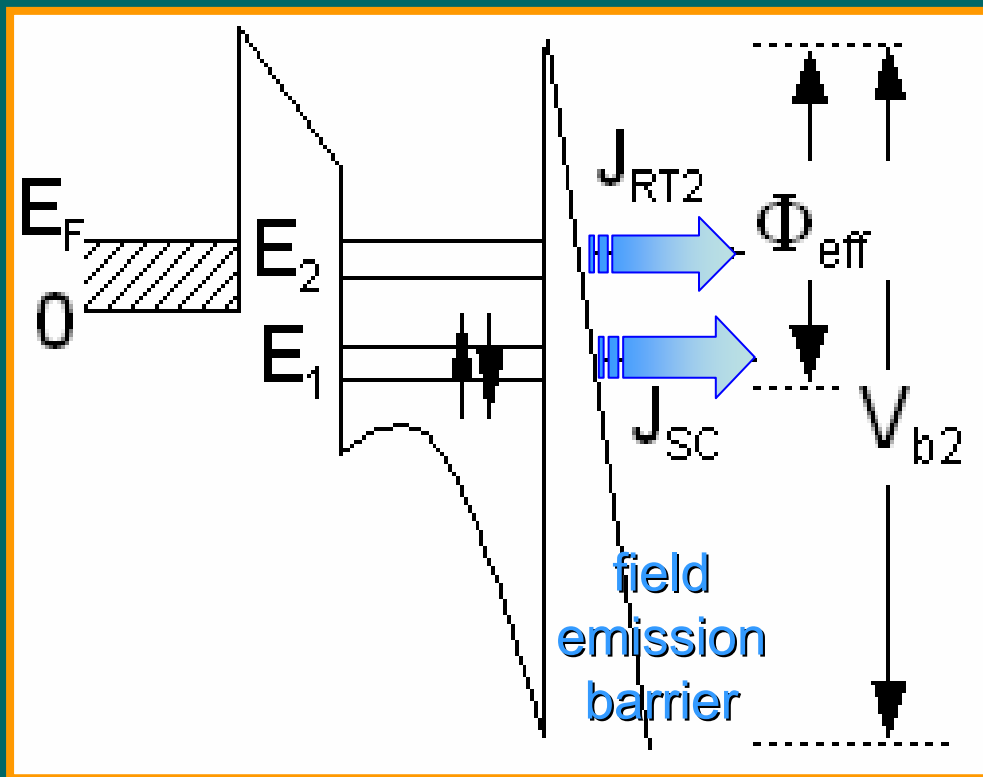
The concept :

- * when the 2D-like quantum state is occupied it creates a space charge in the QW
- * resulting then in an effective lowering of the surface barrier

Nanostructured SSE cathode : field emission mechanism

Lowering of the work function due to space charge in the QW ?

$$\Delta\Phi \equiv V_{b2} - \Phi_{\text{eff}} = V_{\text{SC}}[\text{av}] + 0.5 \times [V(w) - V(0)] + E_1$$



The estimation :

$$m^* = 0.22 m_0, \quad \varepsilon = 8\varepsilon_0$$

$$V_{\text{SC}}[\text{av}] = 0.25 \text{ eV},$$

$$0.5 \times [V(w) - V(0)] = 0.62 \text{ eV},$$

$$\text{and } E_1 = 0.18 \text{ eV} \ \& \ V_{b2} = 1.5 \text{ eV}$$

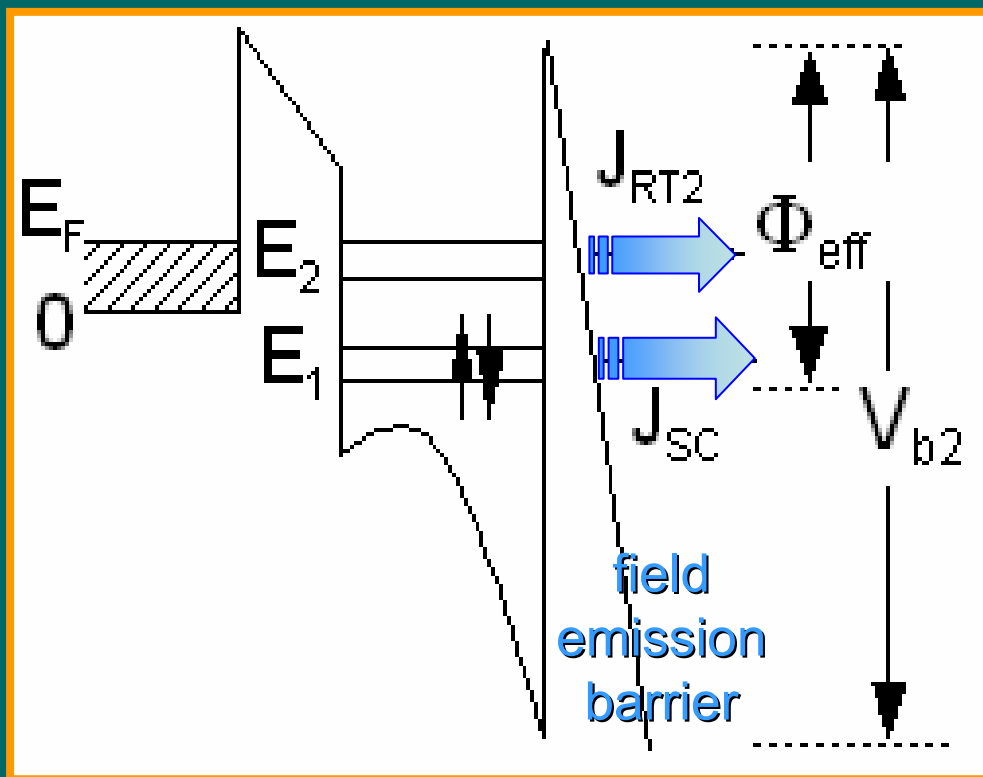
$$\Delta\Phi = 1.05 \text{ eV}$$

value of Φ_{eff} is then 0.45 eV

Nanostructured SSE cathode : field emission mechanism

Lowering of the work function due to space charge in the QW ?

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and $E_1 = 0.18 \text{ eV}$ & $V_{b2} = 1.5 \text{ eV}$

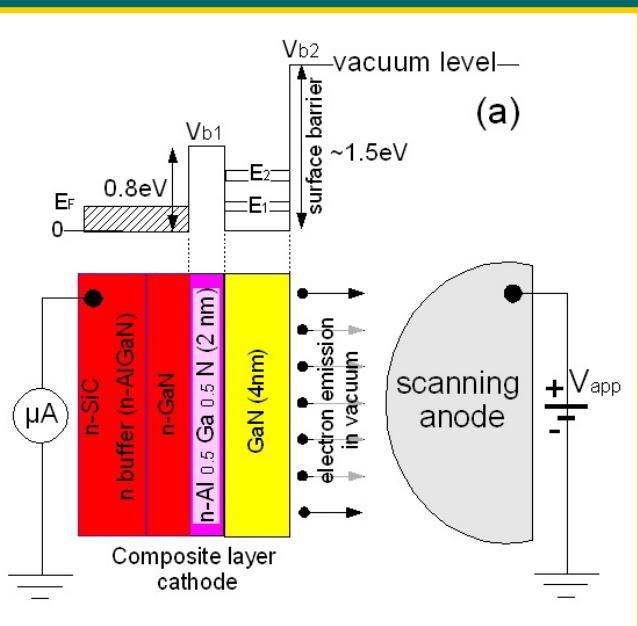
$$\Delta\Phi = 1.05 \text{ eV}$$

value of Φ_{eff} is then 0.45 eV

$$\Phi_{\text{FN}} = (0.53 \text{ to } 0.23 \text{ eV})$$

(experimental values)

Nanostructured SSE cathode : field emission mechanism

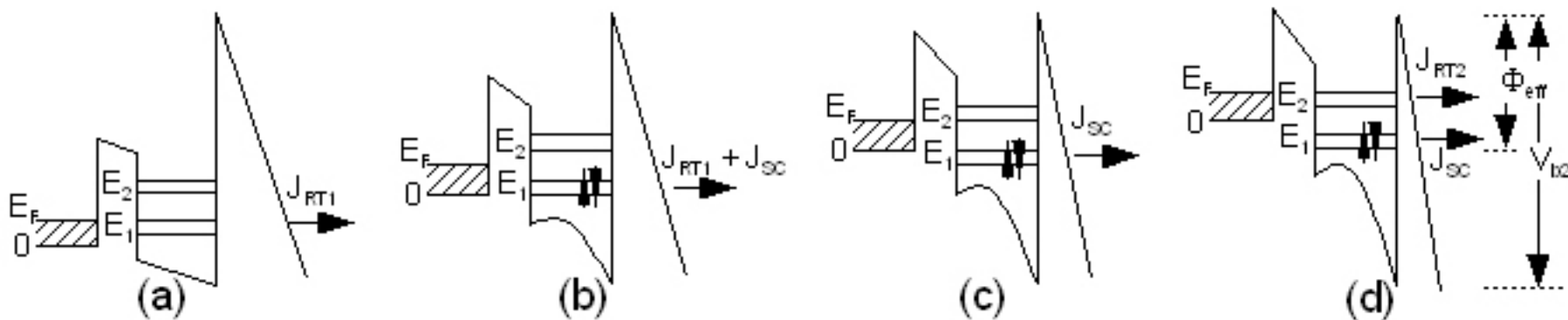


Two-step mechanism

Step 1: Electron injection through the first barrier, the electrons will occupy the sub-bands if they are under the Fermi level

- ➔ space charge formation in the GaN layer
- ➔ lowering of the effective work-function

Step 2: Field emission through the surface barrier
➔ resonant & conventional tunnelling



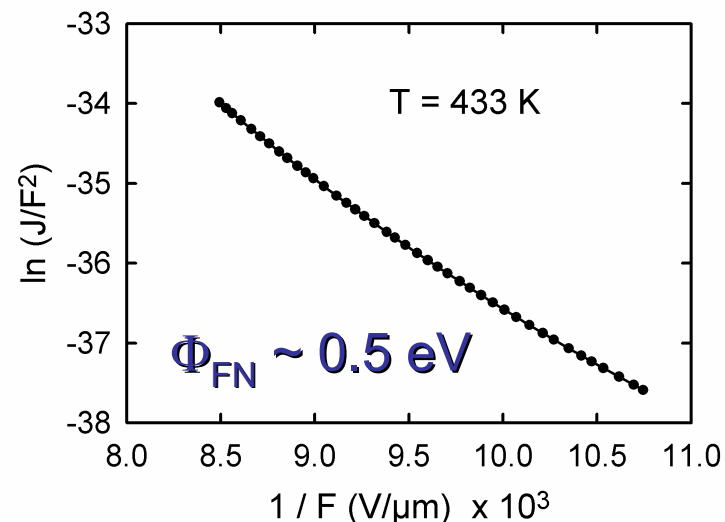
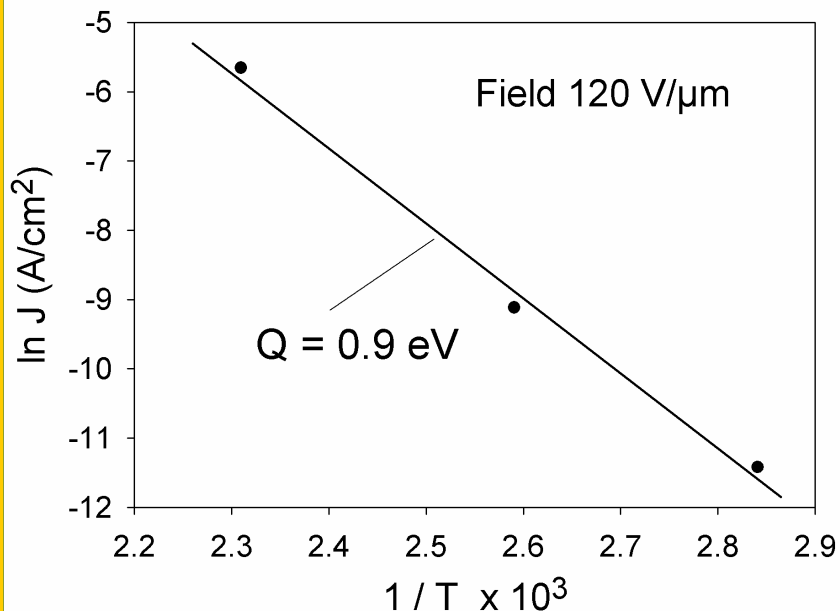
Nanostructured SSE cathode : field emission mechanism

Field dependence for different temperatures

$$J_{FN} = A F^2 \exp(-B\Phi_{FN}^{3/2} / F)$$

Temperature dependence for a given field

$$J_{TH} = A_2 T^2 \exp(-Q / k_B T)$$



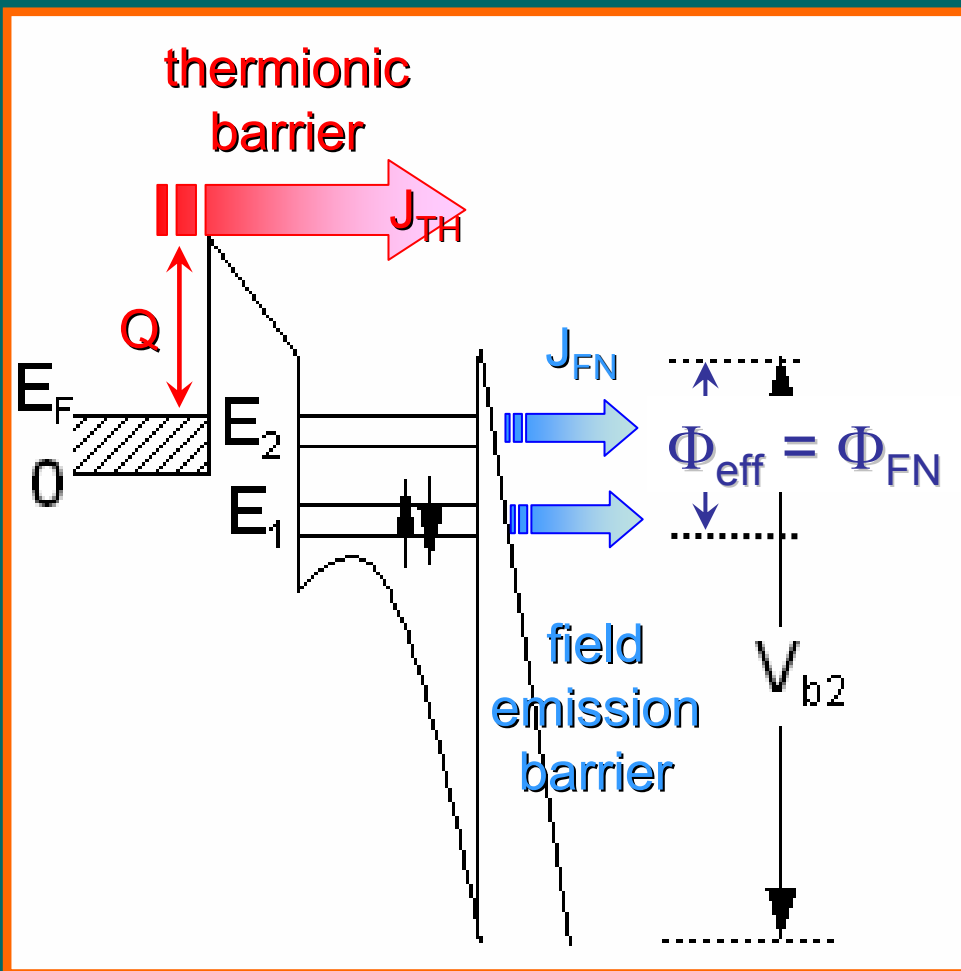
Emitting point 1

T (K)	298	349	383	433
Φ _{FN} (eV)	0.24	0.30	0.27	0.23

Emitting point 2

T (K)	352	383	433	463
Φ _{FN} (eV)	0.53	0.53	0.38	0.31

Nanostructured SSE cathode : dual-barrier model



Field dependence at different temperatures

$$J_{FN} = A F^2 \exp(-B \Phi_{FN}^{3/2} / F)$$

$$\Phi_{FN} \sim 0.5 \text{ eV}$$

Temperature dependence at a given field

$$J_{TH} = A_2 T^2 \exp(-Q / k_B T)$$

$$Q \sim 0.9 \text{ eV}$$

In this dual-barrier model, the measured total emission current, J_{mes} , will be the sum of both contributions, $J_{mes} = J_{FN} + J_{TH}$

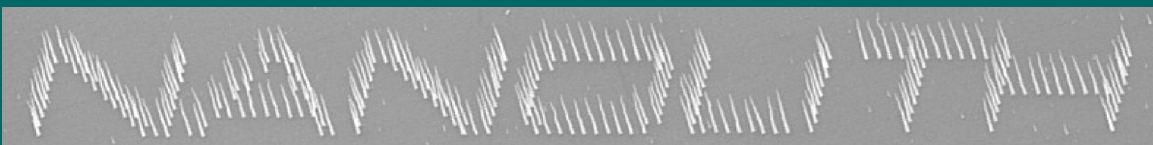
Conclusions and Applications

Spindt-type (1968,1980)	Carbon nanotubes (1991, Lyon 1999)	Carbon nanopearls (Lyon 2003)	SSE cathodes (Lyon 1999,2003)
<p>Small FED, thrusters,</p>	<p>μ-CRT, large FED, (large consumer products), rf-sources, // e- beam lithography, e-gun,</p>		<p>Hard-working environ- ment devices, local cooling, e-microscopy,</p>

Conclusions and Applications

Spindt-type (1968,1980)	Carbon nanotubes (1991, Lyon 1999)	Carbon nanopearls (Lyon 2003)	SSE cathodes (Lyon 1999,2003)
<p>3-D lithography</p>	<p>CVD technology</p> <p>Stable emission under medium or bad vacuum conditions</p>		<p>2-D deposition technol.</p>

Remerciements



Arrays of microguns for parallel e-beam lithography



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6è PCRD

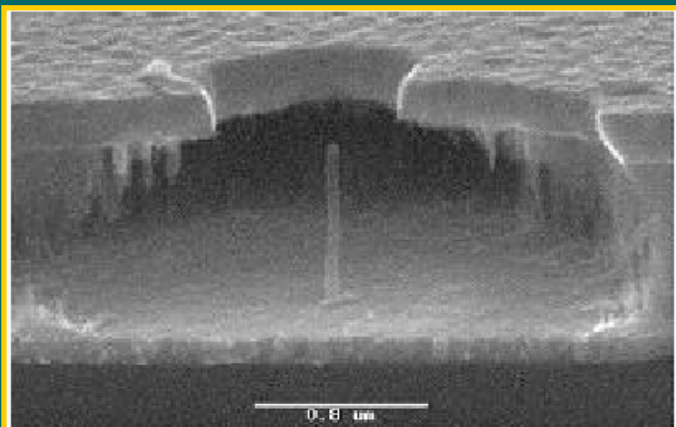


UCBL, Inanov, LETI, IMN, Plassys, Ville de Pau
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Merci de votre attention !



Patterned CNT

